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Fogale Nanotech DEEPROBE 300-M
SN DPB-7DA-001
Vintage +/- 2014

Information contained in this presentation is confidential

Fogale Nanotech DEEPROBE 300-M

SN DPB-7DA-001
Vintage +/- 2014
located Nijmegen the Netherlands

Technology

Low Conherence IR interferometry for step high measurement

Applications

High A/R TSV depth measurement for 200 and 300mm wafer (Via first & Middle)

Benefits

Non destructieve Technology
Fast and easy to use
CCD camera for spot positioning and pattern recognition
Adjustable Metrology spot size
TSV diameter > 2um A:R up to 30
Calibration and maintenance free

SENTECH Senduro 300
SN 33/011
Vintage 2008
located Nijmegen the Netherlands


FOGALE nanotech

Model : DEEPROBE 300-M
P/N : PFPSDEEPROBE300M
S/N : DPB-7DA-001

AC Input : 230V / 900W / 50Hz

CE

125 rue de l'hostellerie - Ville Active
Acti Plus Bât A - 30900 Nîmes
Tel : +33(0)466 620 555 Fax : +33(0)466 627 160

SOS GROUP

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